

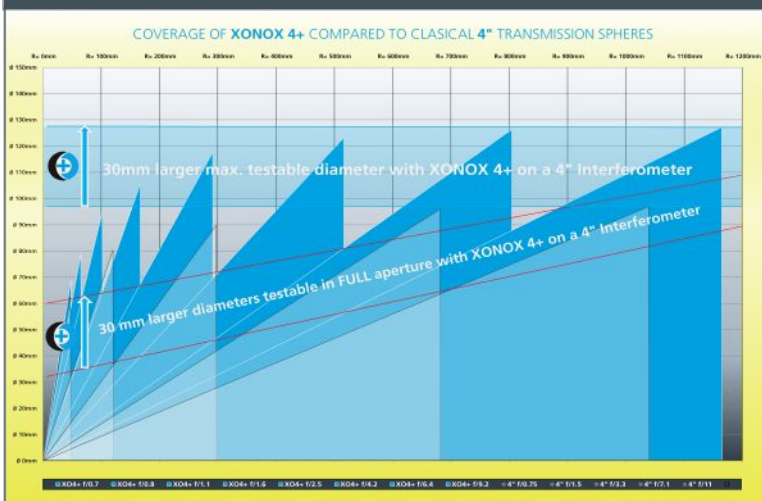
XONOX 4+



5.2" FIZEAU TRANSMISSION SPHERE LINE FOR USE ON 4" INTERFEROMETERS - PROVIDING EXTENDED MEASURING RANGE

- integrated 30% wavefront expansion turns each standard 4" interferometer virtually into a 5.2" system with 30% larger aperture
- no mechanical or optical modification required on existing systems - just mount in existing 4" standard bayonet and start
- fully interchangeable with existing standard 4" TS
- huge added value by up to 60% more coverage of lens surfaces in terms of visible lens aperture and pricing like classical 4" TS
- innovative f/ number line for improved and gap free coverage of many more surfaces for full aperture measurement
- high quality optics, mechanics and innovative assembly for long term sealing against dust
- excellent, hand crafted reference surfaces, free of any features caused by machine- or sub aperture polishing
- „Smart Case“ - the practical, user oriented and safe box- and handling system
- highest quality 100% made at XONOX, Germany

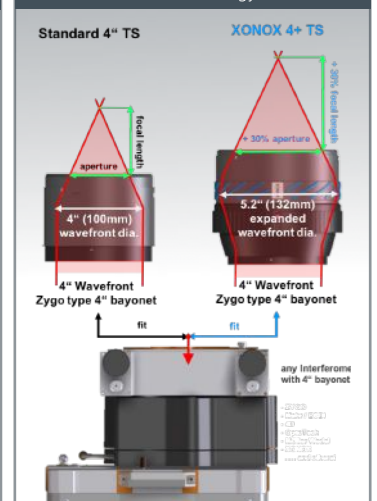
The Added Value



The „SMART CASE“



The Technology



TRANSMISSION SPHERE	f / 0.7	f / 0.8	f / 1.1	f / 1.6	f / 2.5	f / 4.2	f / 6.4	f / 9.2	f / 5.9D	f / ∞
APERTURE ANGLE	91.4°	74.5°	55.4°	36.8	23.3°	13.7°	9.0°	6.3°	9.8°	-
APERTURE DIAMETER [mm]	ø69.7	ø79.0	ø95.0	ø105.4	ø117.5	ø123.2	ø126.3	ø127.1	ø128.0	ø129.5
RADIUS REF. SURFACE [mm]	-48.68	-65.26	-102.21	-167.10	-291.40	-516.60	-804.90	-1164.5	+750.00	flat
HOUSING DIAMETER	ø158 mm									
HOUSING HEIGHT	82.7 mm				58.5 mm		45.5 mm		58.5 mm	45.5 mm
QUALITY OF REF. SURFACE	BASE Line: λ/10 PV • PRO Line: λ/20 PV • PRIME Line: λ/50 PV (@ 632.8 nm)									
MECHANICAL CONNECTION	ZYGO compatible 4" bayonet									

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METROLOGY FOR OPTICS REDEFINED